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Continuation Sheet

1. Regarding claim 50, Applicant argues that Kuwashiro does not teach or suggest providing an input terminal of a drive circuit directly or via another component with input signals via an arrangement of test contact areas to generate a test pattern on a matrix of picture element as set forth in claim 50. The Examiner respectfully disagrees. Kuwashiro shows (Fig. 3) wherein the test contacts [651-2, 651-2] are electrically connected to dummy pads [731-1, 731-2]. Dummy pads [731-1, 731-2] are electrically connected to interconnections [753-1, 753-2]. Interconnections [753-1, 753-2] are electrically to data interconnections [783]. Interconnections [783] are also electrically connected to operational contact areas [641]. Test pattern (horizontal clock signal (CKH), horizontal start signal (STH) or digital image data (DDSR)) will be transmitted through interconnections [783] to the display device in order to detect if desired signals are being supplied. Since the test pattern supplied to interconnection 783 will be passing through test contacts [651-2, 651-2] and the final destination of the test pattern is the display device, broadly, it can interpreted that Kuwashiro discloses providing an input terminal of a drive circuit with input signals via an arrangement of test contact areas to generate a test pattern on a matrix of picture element (Col. 6, Ln 36 through Col. 7, Ln 67). Therefor, Kuwashiro does teach or suggest providing an input terminal of a drive circuit directly or via another component with input signals via an arrangement of test contact areas to generate a test pattern on a matrix of picture element as set forth in claim 50.

2. Regarding claim 50, Applicant also argues that Kuwashiro also does not teach or suggest testing picture elements of a matrix of picture elements as set forth in claim 50. The Examiner respectfully disagrees. Kuwashiro discloses if a defect is present in the **image displayed** on the active matrix liquid crystal display 1, a probe makes contact with the dummy terminals 651-1, 651-2 successively to see if desired signals are being supplied (Col. 7, Ln 43-47). Any ordinary skill in the art would recognize that the elements displaying an image would be the picture elements [2]. In other words, Kuwashiro implicitly discloses testing the picture elements by detecting if desired signals are being supplied. Therefor, Kuwashiro does teach or suggest testing picture elements of a matrix of picture elements as set forth in claim 50.

/Ha T. Nguyen/

Supervisory Patent Examiner, Art Unit 2829